

54AC245 • 54ACT245 Octal Bidirectional Transceiver with TRI-STATE® Inputs/Outputs

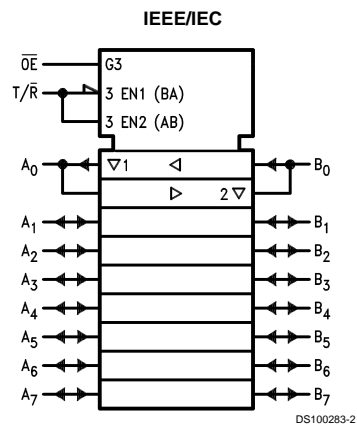
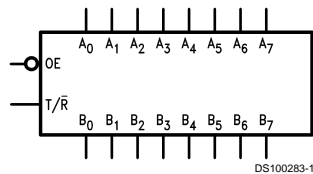
General Description

The 'AC/ACT245 contains eight non-inverting bidirectional buffers with TRI-STATE outputs and is intended for bus-oriented applications. Current sinking capability is 24 mA at both the A and B ports. The Transmit/Receive (T/R) input determines the direction of data flow through the bidirectional transceiver. Transmit (active-HIGH) enables data from A ports to B ports; Receive (active-LOW) enables data from B ports to A ports. The Output Enable input, when HIGH, disables both A and B ports by placing them in a HIGH Z condition.

Features

- I_{CC} and I_{OZ} reduced by 50%
- Noninverting buffers
- Bidirectional data path
- A and B outputs source/sink 24 mA
- 'ACT245 has TTL-compatible inputs
- Standard Microcircuit Drawing (SMD)
 - 'AC245: 5962-87758
 - 'ACT245: 5962-87663

Logic Symbols

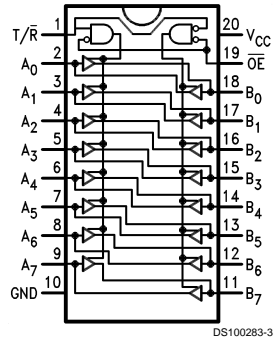


Pin Names	Description
OE	Output Enable Input
T/R	Transmit/Receive Input
A ₀ -A ₇	Side A TRI-STATE Inputs or TRI-STATE Outputs
B ₀ -B ₇	Side B TRI-STATE Inputs or TRI-STATE Outputs

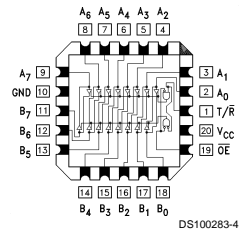
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Connection Diagrams

Pin Assignment for
DIP and Flatpak



Pin Assignment for LCC



Truth Table

Inputs		Outputs
OE	T/R	
L	L	Bus B Data to Bus A
L	H	Bus A Data to Bus B
H	X	HIGH-Z State

H = HIGH Voltage Level
L = LOW Voltage Level
X = Immaterial

Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Supply Voltage (V_{CC})	-0.5V to +7.0V
DC Input Diode Current (I_{IK})	
$V_I = -0.5V$	-20 mA
$V_I = V_{CC} + 0.5V$	+20 mA
DC Input Voltage (V_I)	-0.5V to $V_{CC} + 0.5V$
DC Output Diode Current (I_{OK})	
$V_O = -0.5V$	-20 mA
$V_O = V_{CC} + 0.5V$	+20 mA
DC Output Voltage (V_O)	-0.5V to $V_{CC} + 0.5V$
DC Output Source or Sink Current (I_O)	±50 mA
DC V_{CC} or Ground Current per Output Pin (I_{CC} or I_{GND})	±50 mA
Storage Temperature (T_{STG})	-65°C to +150°C
Junction Temperature (T_J)	
CDIP	175°C

Recommended Operating Conditions

Supply Voltage (V_{CC})	
'AC	2.0V to 6.0V
'ACT	4.5V to 5.5V
Input Voltage (V_I)	0V to V_{CC}
Output Voltage (V_O)	0V to V_{CC}
Operating Temperature (T_A)	
54AC/ACT	-55°C to +125°C
Minimum Input Edge Rate ($\Delta V/\Delta t$)	
'AC Devices	
V_{IN} from 30% to 70% of V_{CC}	
V_{CC} @ 3.3V, 4.5V, 5.5V	125 mV/ns
Minimum Input Edge Rate ($\Delta V/\Delta t$)	
'ACT Devices	
V_{IN} from 0.8V to 2.0V	
V_{CC} @ 4.5V, 5.5V	125 mV/ns

Note 1: Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. National does not recommend operation of FACT® circuits outside databook specifications.

DC Characteristics for 'AC Family Devices

Symbol	Parameter	V_{CC} (V)	54AC	Units	Conditions	
			$T_A =$ -55°C to +125°C			
			Guaranteed Limits			
V_{IH}	Minimum High Level Input Voltage	3.0	2.1	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$	
		4.5	3.15			
		5.5	3.85			
V_{IL}	Maximum Low Level Input Voltage	3.0	0.9	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$	
		4.5	1.35			
		5.5	1.65			
V_{OH}	Minimum High Level Output Voltage	3.0	2.9	V	$I_{OUT} = -50 \mu A$	
		4.5	4.4			
		5.5	5.4			
			3.0	2.4	V	(Note 2) $V_{IN} = V_{IL}$ or V_{IH} -12 mA I_{OH} -24 mA -24 mA
			4.5	3.7		
			5.5	4.7		
V_{OL}	Maximum Low Level Output Voltage	3.0	0.1	V	$I_{OUT} = 50 \mu A$	
		4.5	0.1			
		5.5	0.1			
			3.0	0.50	V	(Note 2) $V_{IN} = V_{IL}$ or V_{IH} 12 mA I_{OL} 24 mA 24 mA
			4.5	0.50		
			5.5	0.50		
I_{IN}	Maximum Input Leakage Current	5.5	±1.0	μA	$V_I = V_{CC}, GND$	

DC Characteristics for 'AC Family Devices (Continued)

Symbol	Parameter	V _{CC} (V)	54AC	Units	Conditions
			T _A = -55°C to +125°C		
			Guaranteed Limits		
I _{OLD}	(Note 3) Minimum Dynamic Output Current	5.5	50	mA	V _{OLD} = 1.65V Max
I _{OHD}		5.5	-50	mA	V _{OHD} = 3.85V Min
I _{CC}	Maximum Quiescent Supply Current	5.5	80.0	μA	V _{IN} = V _{CC} or GND
I _{OZT}	Maximum I/O Leakage Current	5.5	±5.5	μA	V _{I(OE)} = V _{IL} , V _{IH} V _I = V _{CC} , GND V _O = V _{CC} , GND

Note 2: All outputs loaded; thresholds on input associated with output under test.

Note 3: Maximum test duration 2.0 ms, one output loaded at a time.

Note 4: I_{IN} and I_{CC} @ 3.0V are guaranteed to be less than or equal to the respective limit @ 5.5V V_{CC}.

I_{CC} for 54AC @ 25°C is identical to 74AC @ 25°C.

DC Characteristics for 'ACT Family Devices

Symbol	Parameter	V _{CC} (V)	54ACT	Units	Conditions	
			T _A = -55°C to +125°C			
			Guaranteed Limits			
V _{IH}	Minimum High Level Input Voltage	4.5	2.0	V	V _{OUT} = 0.1V or V _{CC} - 0.1V	
		5.5	2.0			
V _{IL}	Maximum Low Level Input Voltage	4.5	0.8	V	V _{OUT} = 0.1V or V _{CC} - 0.1V	
		5.5	0.8			
V _{OH}	Minimum High Level Output Voltage	4.5	4.4	V	I _{OUT} = -50 μA	
		5.5	5.4			
			4.5	3.70	V	(Note 5) V _{IN} = V _{IL} or V _{IH} I _{OH} -24 mA -24 mA
			5.5	4.70		
V _{OL}	Maximum Low Level Output Voltage	4.5	0.1	V	I _{OUT} = 50 μA	
		5.5	0.1			
			4.5	0.50	V	(Note 5) V _{IN} = V _{IL} or V _{IH} I _{OL} 24 mA 24 mA
			5.5	0.50		
I _{IN}	Maximum Input Leakage Current	5.5	±1.0	μA	V _I = V _{CC} , GND	
I _{CC(T)}	Maximum I _{CC} /Input	5.5	1.6	mA	V _I = V _{CC} - 2.1V	
I _{OLD}	(Note 6) Minimum Dynamic Output Current	5.5	50	mA	V _{OLD} = 1.65V Max	
I _{OHD}		5.5	-50	mA	V _{OHD} = 3.85V Min	
I _{CC}	Maximum Quiescent Supply Current	5.5	80.0	μA	V _{IN} = V _{CC} or GND	

DC Characteristics for 'ACT Family Devices (Continued)

Symbol	Parameter	V _{CC} (V)	54ACT		Units	Conditions
			T _A = -55°C to +125°C			
			Guaranteed Limits			
I _{OZT}	Maximum I/O Leakage Current	5.5	±5.0		µA	V _I (OE) = V _{IL} , V _{IH} V _I = V _{CC} , GND V _O = V _{CC} , GND

Note 5: All outputs loaded; thresholds on input associated with output under test.

Note 6: Maximum test duration 2.0 ms, one output loaded at a time.

Note 7: I_{CC} for 54ACT @ 25°C is identical to 74ACT @ 25°C.

AC Electrical Characteristics

Symbol	Parameter	V _{CC} (V) (Note 8)	54AC		Units	Fig. No.
			T _A = -55°C to +125°C			
			C _L = 50 pF			
			Min	Max		
t _{PLH}	Propagation Delay A _n to B _n or B _n to A _n	3.3	1.0	11.5	ns	
		5.0	1.0	8.5		
t _{PHL}	Propagation Delay A _n to B _n or B _n to A _n	3.3	1.0	10.0	ns	
		5.0	1.0	7.5		
t _{PZH}	Output Enable Time	3.3	1.0	13.5	ns	
		5.0	1.0	10.0		
t _{PZL}	Output Enable Time	3.3	1.0	14.5	ns	
		5.0	1.0	10.5		
t _{PHZ}	Output Disable Time	3.3	1.0	13.5	ns	
		5.0	1.0	10.5		
t _{PLZ}	Output Disable Time	3.3	1.0	14.0	ns	
		5.0	1.0	10.5		

Note 8: Voltage Range 3.3 is 3.3V ±0.3V

Voltage Range 5.0 is 5.0V ±0.5V

AC Electrical Characteristics

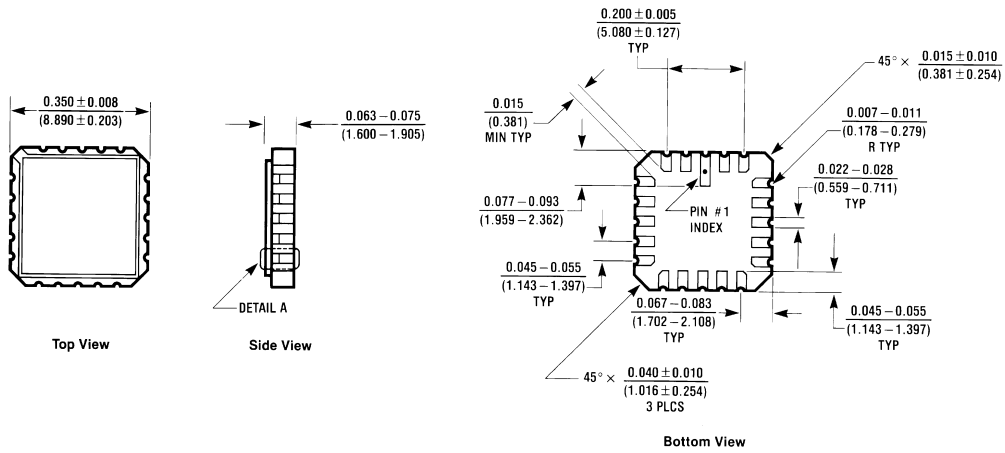
Symbol	Parameter	V _{CC} (V) (Note 9)	54ACT		Units
			T _A = -55°C to +125°C		
			C _L = 50 pF		
			Min	Max	
t _{PLH}	Propagation Delay A _n to B _n or B _n to A _n	5.0	1.0	9.0	ns
t _{PHL}	Propagation Delay A _n to B _n or B _n to A _n	5.0	1.0	10.0	ns
t _{PZH}	Output Enable Time	5.0	1.0	12.0	ns
t _{PZL}	Output Enable Time	5.0	1.0	13.0	ns
t _{PHZ}	Output Disable Time	5.0	1.0	12.0	ns
t _{PLZ}	Output Disable Time	5.0	1.0	12.0	ns

Note 9: Voltage Range 5.0 is 5.0V ±0.5V

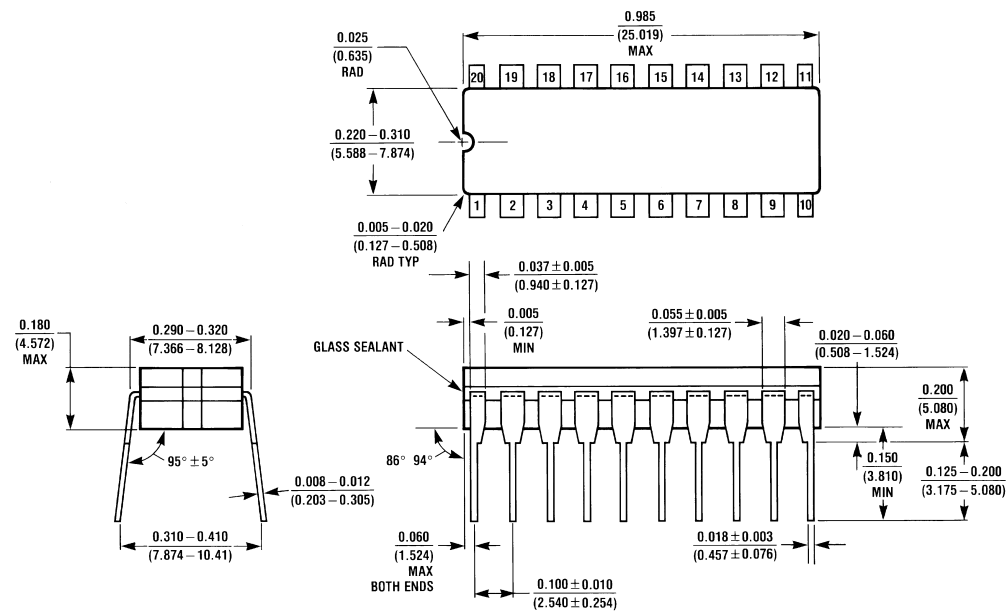
Capacitance

Symbol	Parameter	Typ	Units	Conditions
C_{IN}	Input Capacitance	4.5	pF	$V_{CC} = OPEN$
$C_{I/O}$	Input/Output Capacitance	15.0	pF	$V_{CC} = 5.0V$
C_{PD}	Power Dissipation Capacitance	45.0	pF	$V_{CC} = 5.0V$

Physical Dimensions inches (millimeters) unless otherwise noted

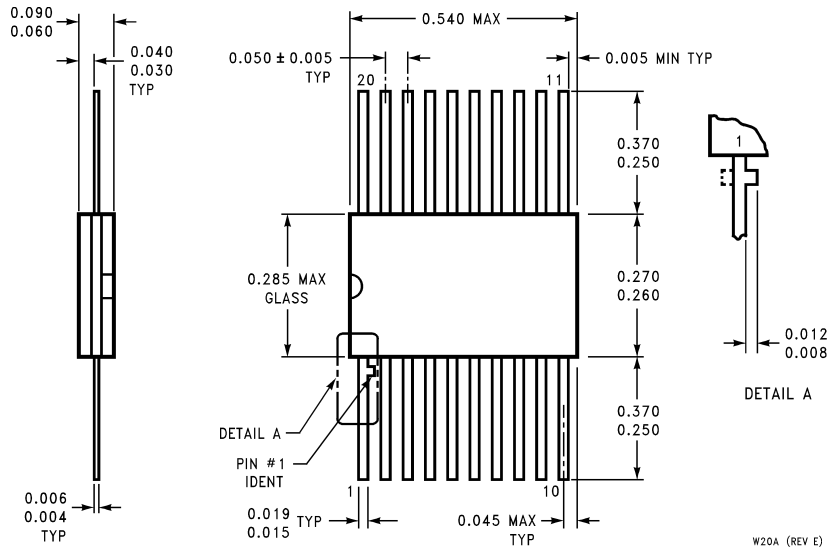


20 Terminal Ceramic Leadless Chip Carrier (L)
NS Package Number E20A



20-Lead Ceramic Dual-In-Line Package (D)
NS Package Number J20A

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



**20-Lead Ceramic Flatpak (F)
NS Package Number W20A**

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